

<b>Notice of References Cited</b>	Application/Control No. 10/001,992	Applicant(s)/Patent Under Reexamination TANAKA, RITSUKO ET AL	
	Examiner John L Young	Art Unit 3622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,064,979	05-2000	Perkowski, Thomas J.	705/26
	B	US-5,724,521	03-1998	Dedrick, Rick	705/26
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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